


<b>Search Notes</b>  	<b>Application/Control No.</b>  10686553	<b>Applicant(s)/Patent Under Reexamination</b>  WALSH, PATRICK JAY
	<b>Examiner</b>  David Q Nguyen	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	456.1	03/05/08	DN
455	456.2	03/05/08	DN
455	456.3	03/05/08	DN
455	456.6	03/05/08	DN
455	411	03/05/08	DN
455	414	03/05/08	DN
455	415	03/05/08	DN
455	456	03/05/08	DN
455	445	03/05/08	DN
370	331	03/05/08	DN
370	329	03/05/08	DN
370	338	03/05/08	DN

SEARCH NOTES			
Search Notes		Date	Examiner
East search		03/05/08	DN
Text search		03/05/08	DN
Interference search printout		03/05/08	DN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
PGPUB Text search		03/05/08	DN
See interference search printout		03/05/08	DN